Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/772,292	LEE ET AL.
Examiner	Art Unit

2618

SIMON D. NGUYEN

SEARCHED					
Class	Subclass	Date	Examiner		
455	232.1	6/29/2006	SDN		
_	234.1				
	234.2				
	239.1-				
	241.1				
	245.1-				
	253.2				
	63.1				
375	317-319				
	345				
		7			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	6/29/2006	SDN	